

Notice of References Cited	Application/Control No. 09/576,681	Applicant(s)/Patent Under Reexamination CHIBA ET AL.	
	Examiner Lynne Edmondson	Art Unit 1725	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,160,603	12-2000	Tanaka et al.	345/103
*	B	US-5,477,309	12-1995	Ota et al.	355/53
*	C	US-2003/0015806	01-2003	Chiba et al.	430/30
*	D	US-6,437,454	08-2002	Chiba et al.	257/798
*	E	US-6,436,842	08-2002	Chiba et al.	438/758
*	F	US-6,429,889	08-2002	Murokh, Igor Y.	347/224
*	G	US-6,144,397	11-2000	Chiba et al.	347/241
*	H	US-2001/0006399	07-2001	Chiba, Teiichirou	347/224
*	I	US-6,068,891	05-2000	O'Dell et al.	360/135
*	J	US-4,847,183	07-1989	Kruger, James B.	430/322
*	K	US-3,623,603	11-1971	Casner et al.	209/3.3
*	L	US-6,265,119	07-2001	Magome, Nobutaka	430/30
*	M	US-6,267,005	07-2001	Samsavar et al.	73/105

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP-6-226472-A	08-1994	Japan	Takehisa et al.	
*	O	JP-6-7971-A	01-1994	Japan	Takehisa et al.	
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.